



SEMiX® 5

Trench IGBT Modules

Engineering Sample SEMiX405GARL07E3

Target Data

Features

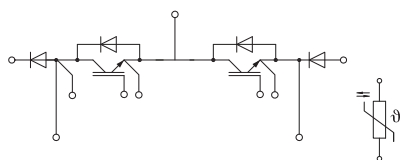
- Solderless assembling solution with PressFIT signal pins and screw power terminals
- IGBT Trench Gate Technology
- $V_{CE(sat)}$ with positive temperature coefficient
- Low inductance case
- Reliable mechanical design with injection moulded terminals and reliable internal connections
- UL recognized file no. E63532
- NTC temperature sensor inside

Typical Applications*

- UPS
- 3 Level Inverters

Remarks

- Case temperature limited to $T_C=125^\circ$ max.
- Product reliability results are valid for $T_{jop}=150^\circ\text{C}$
- Dynamic data are estimated
- For storage and case temperature with TIM see document "TP(HALA P8) SEMiX 5p"



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Absolute Maximum Ratings

Symbol	Conditions	Values	Unit
IGBT			
V_{CES}	$T_j = 25^\circ\text{C}$	650	V
I_C	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	457
		$T_c = 80^\circ\text{C}$	343
I_{Cnom}		400	A
I_{CRM}	$I_{CRM} = 3 \times I_{Cnom}$	1200	A
V_{GES}		-20 ... 20	V
t_{psc}	$V_{CC} = 360\text{ V}$ $V_{GE} \leq 15\text{ V}$ $V_{CES} \leq 650\text{ V}$	$T_j = 150^\circ\text{C}$	6
T_j		-40 ... 175	$^\circ\text{C}$

Inverse diode

V_{RRM}	$T_j = 25^\circ\text{C}$	650	V
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	86
		$T_c = 80^\circ\text{C}$	64
I_{Fnom}		50	A
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$	100	A
I_{FSM}	$t_p = 10\text{ ms, sin } 180^\circ, T_j = 25^\circ\text{C}$	550	A
T_j		-40 ... 175	$^\circ\text{C}$

Freewheeling diode

V_{RRM}	$T_j = 25^\circ\text{C}$	650	V
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	484
		$T_c = 80^\circ\text{C}$	353
I_{Fnom}		400	A
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$	800	A
I_{FSM}	$t_p = 10\text{ ms, sin } 180^\circ, T_j = 25^\circ\text{C}$	2646	A
T_j		-40 ... 175	$^\circ\text{C}$

Module

$I_{t(RMS)}$		450	A
T_{stg}	module without TIM	-40 ... 125	$^\circ\text{C}$
V_{isol}	AC sinus 50Hz, $t = 1\text{ min}$	4000	V

Characteristics

Symbol	Conditions	min.	typ.	max.	Unit
IGBT					
$V_{CE(sat)}$	$I_C = 400\text{ A}$ $V_{GE} = 15\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	1.45	1.90	V
		$T_j = 150^\circ\text{C}$	1.70	2.10	V
V_{CE0}	chipelevel	$T_j = 25^\circ\text{C}$	0.90	1.00	V
		$T_j = 150^\circ\text{C}$	0.82	0.90	V
r_{CE}	$V_{GE} = 15\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	1.38	2.3	m Ω
		$T_j = 150^\circ\text{C}$	2.2	3.0	m Ω
$V_{GE(th)}$	$V_{GE}=V_{CE}, I_C = 6.4\text{ mA}$	5.1	5.8	6.4	V
I_{CES}	$V_{GE} = 0\text{ V}$ $V_{CE} = 650\text{ V}$	$T_j = 25^\circ\text{C}$	0.12	0.3	mA
		$T_j = 150^\circ\text{C}$	-	-	mA
C_{ies}	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$	24.7		nF
C_{oes}	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$	1.54		nF
C_{res}	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$	0.73		nF
Q_G	$V_{GE} = -15\text{ V} \dots +15\text{ V}$		5139		nC
R_{Gint}	$T_j = 25^\circ\text{C}$		1.0		Ω



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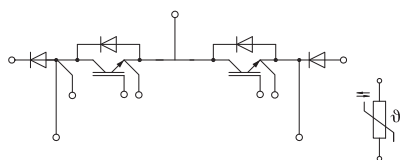
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- UPS
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Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
IGBT						
t _{d(on)}	V _{CC} = 300 V	T _j = 150 °C		220		ns
t _r	I _C = 400 A	T _j = 150 °C		220		ns
E _{on}	V _{GE} = +15/-15 V	T _j = 150 °C		27.91		mJ
t _{d(off)}	R _{G on} = 10 Ω	T _j = 150 °C		1120		ns
t _f	R _{G off} = 10 Ω	T _j = 150 °C		103		ns
E _{off}	di/dt _{on} = 2038 A/μs di/dt _{off} = 3960 A/μs du/dt = 3052 V/μs	T _j = 150 °C		27.89		mJ
R _{th(j-c)}	per IGBT			0.14		K/W
R _{th(c-s)}	per IGBT (λgrease=0.81 W/mK, thickness 50-100μm)			0.06		K/W
R _{th(c-s)}	per IGBT (λ=3.4 W/mK)			t.b.d.		K/W
Inverse diode						
V _F = V _{EC}	I _F = 50 A	T _j = 25 °C		1.37	1.73	V
	V _{GE} = 0 V chiplevel	T _j = 150 °C		1.35	1.72	V
V _{F0}	chiplevel	T _j = 25 °C		1.04	1.24	V
		T _j = 150 °C		0.85	0.99	V
r _F	chiplevel	T _j = 25 °C		6.7	9.8	mΩ
		T _j = 150 °C		10	15	mΩ
I _{RRM}	I _F = 50 A	T _j = 150 °C		-		A
Q _{rr}		T _j = 150 °C		-		μC
E _{rr}		T _j = 150 °C		-		mJ
R _{th(j-c)}	per diode			0.81		K/W
R _{th(c-s)}	per diode (λgrease=0.81 W/mK, thickness 50-100μm)			0.082		K/W
R _{th(c-s)}	per diode (λ=3.4 W/mK)			t.b.d.		K/W
Freewheeling diode						
V _F = V _{EC}	I _F = 400 A	T _j = 25 °C		1.39	1.75	V
	V _{GE} = 0 V chiplevel	T _j = 150 °C		1.38	1.76	V
V _{F0}	chiplevel	T _j = 25 °C		1.04	1.236	V
		T _j = 150 °C		0.85	0.99	V
r _F	chiplevel	T _j = 25 °C		0.88	1.30	mΩ
		T _j = 150 °C		1.32	1.93	mΩ
I _{RRM}	I _F = 400 A di/dt _{off} = 2038 A/μs	T _j = 150 °C		188.2		A
Q _{rr}		T _j = 150 °C		37		μC
E _{rr}		T _j = 150 °C		6.27		mJ
R _{th(j-c)}	per diode			0.17		K/W
R _{th(c-s)}	per diode (λgrease=0.81 W/mK, thickness 50-100μm)			0.069		K/W
R _{th(c-s)}	per diode (λ=3.4 W/mK)			t.b.d.		K/W



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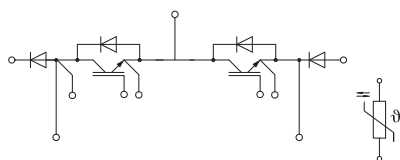
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Characteristics

Symbol	Conditions	min.	typ.	max.	Unit
Module					
L_{CE}			30		nH
$R_{CC'+EE'}$	measured per switch	$T_C = 25^\circ\text{C}$	0.8		m Ω
		$T_C = 125^\circ\text{C}$	1.1		m Ω
$R_{th(c-s)1}$	calculated without thermal coupling		0.017		K/W
$R_{th(c-s)2}$	including thermal coupling, T_s underneath module ($\lambda_{grease}=0.81\text{ W/(m}^2\text{K)}$)		t.b.d.		K/W
$R_{th(c-s)2}$	including thermal coupling, T_s underneath module, pre-applied phase change material		t.b.d.		K/W
M_s	to heat sink (M5)	3		6	Nm
M_t					
	to terminals (M6)	3		6	Nm
					Nm
w			398		g
Temperature Sensor					
R_{100}	$T_C=100^\circ\text{C}$ ($R_{25}=5\text{ k}\Omega$)		$493 \pm 5\%$		Ω
$B_{100/125}$	$R(T)=R_{100}\exp[B_{100/125}(1/T-1/T_{100})]$; $T[K]$		$3550 \pm 2\%$		K



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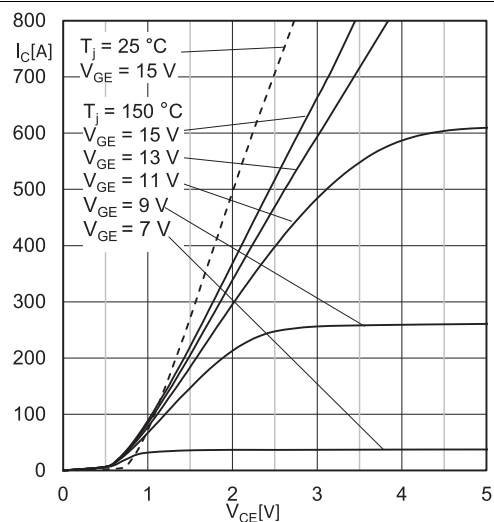


Fig. 1: Typ. output characteristic, inclusive $R_{CC'} + EE'$

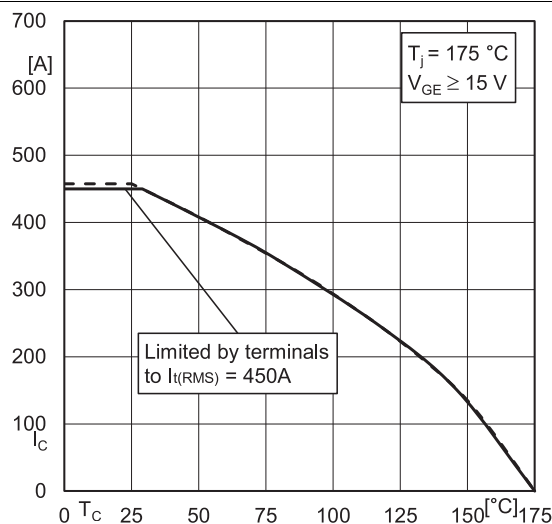


Fig. 2: Rated current vs. temperature $I_C = f(T_C)$

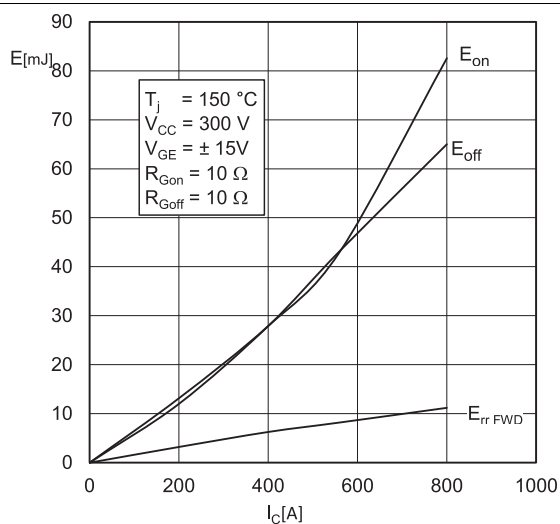


Fig. 3: Typ. turn-on /-off energy = $f(I_C)$

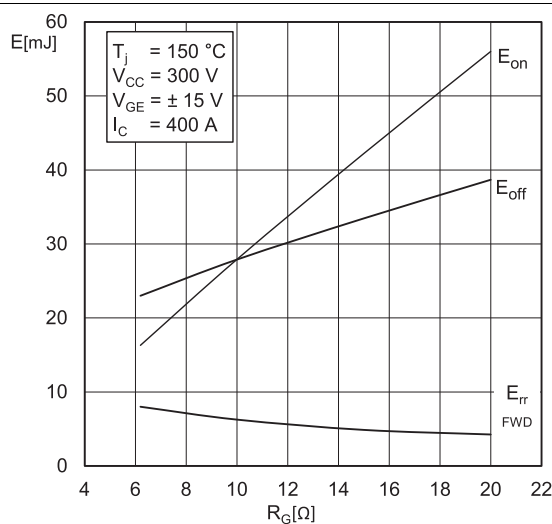


Fig. 4: Typ. turn-on /-off energy = $f(R_G)$

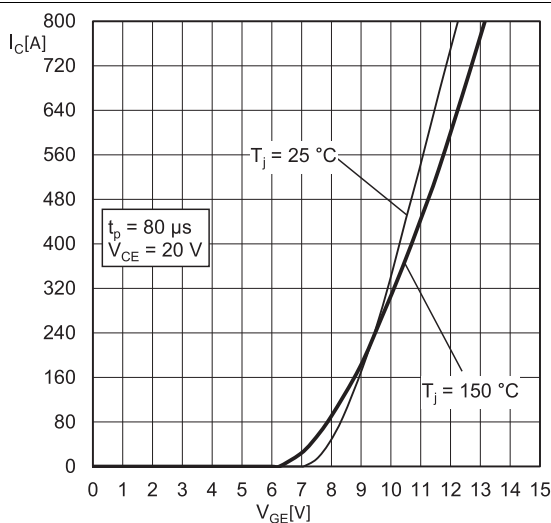


Fig. 5: Typ. transfer characteristic

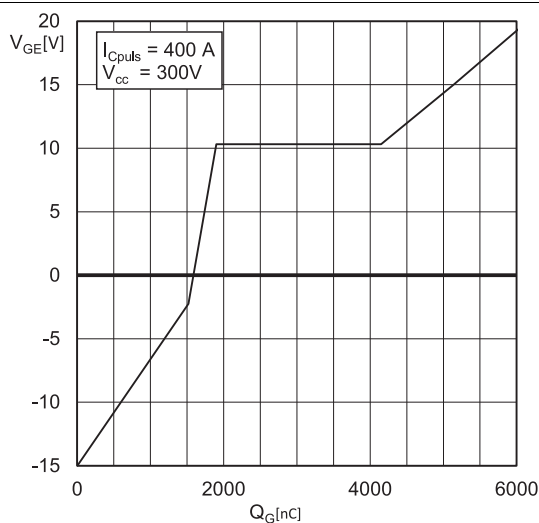
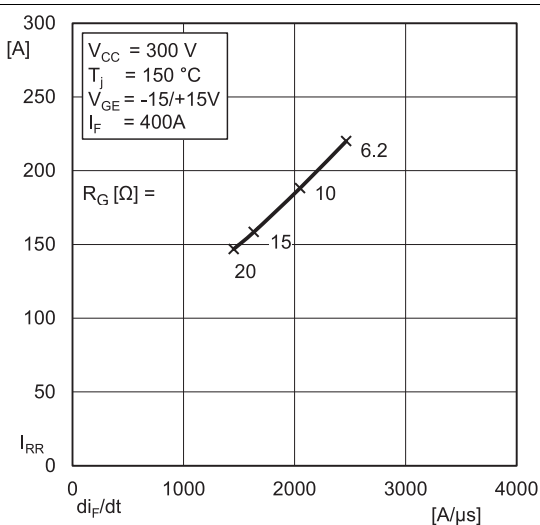
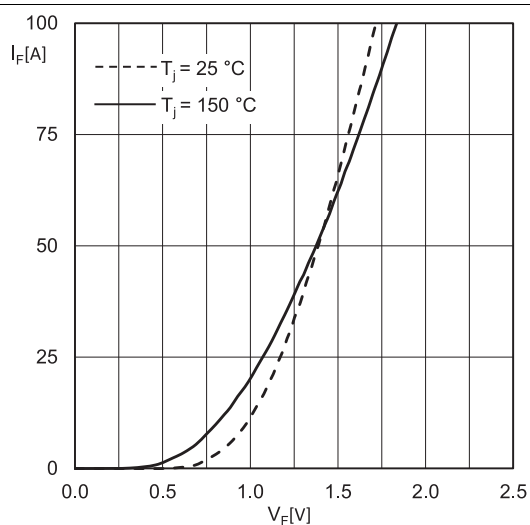
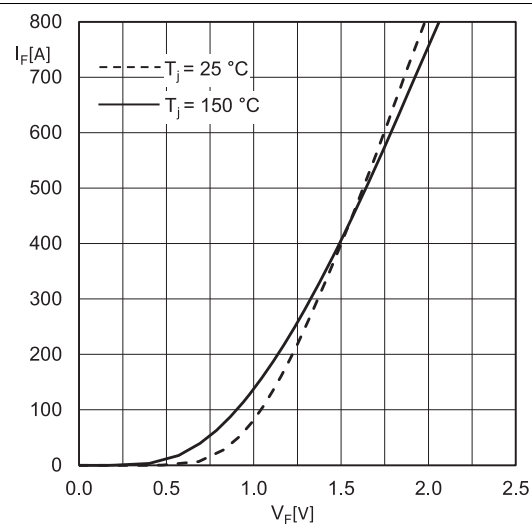
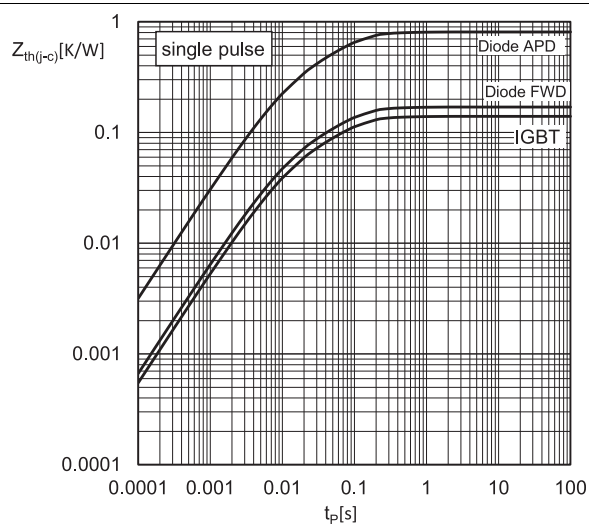
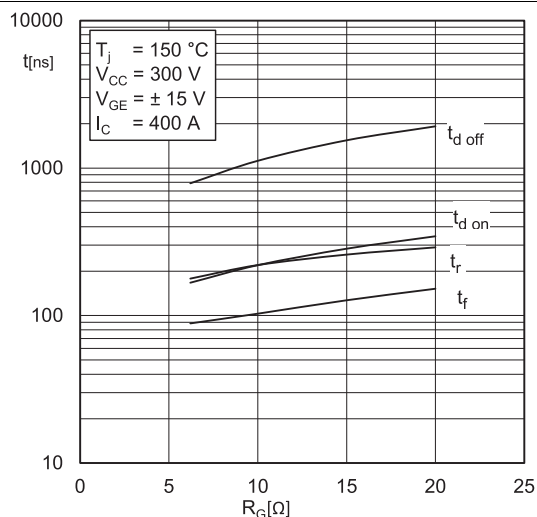
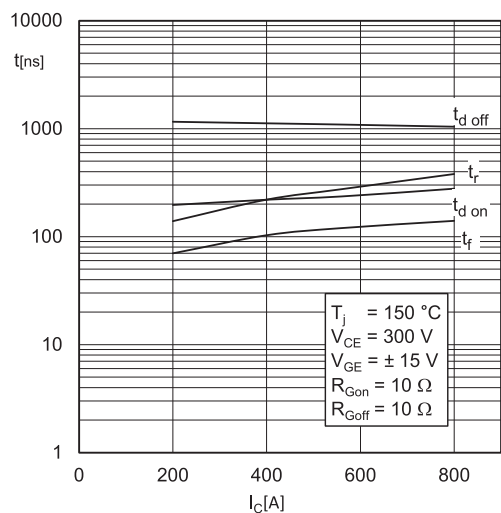
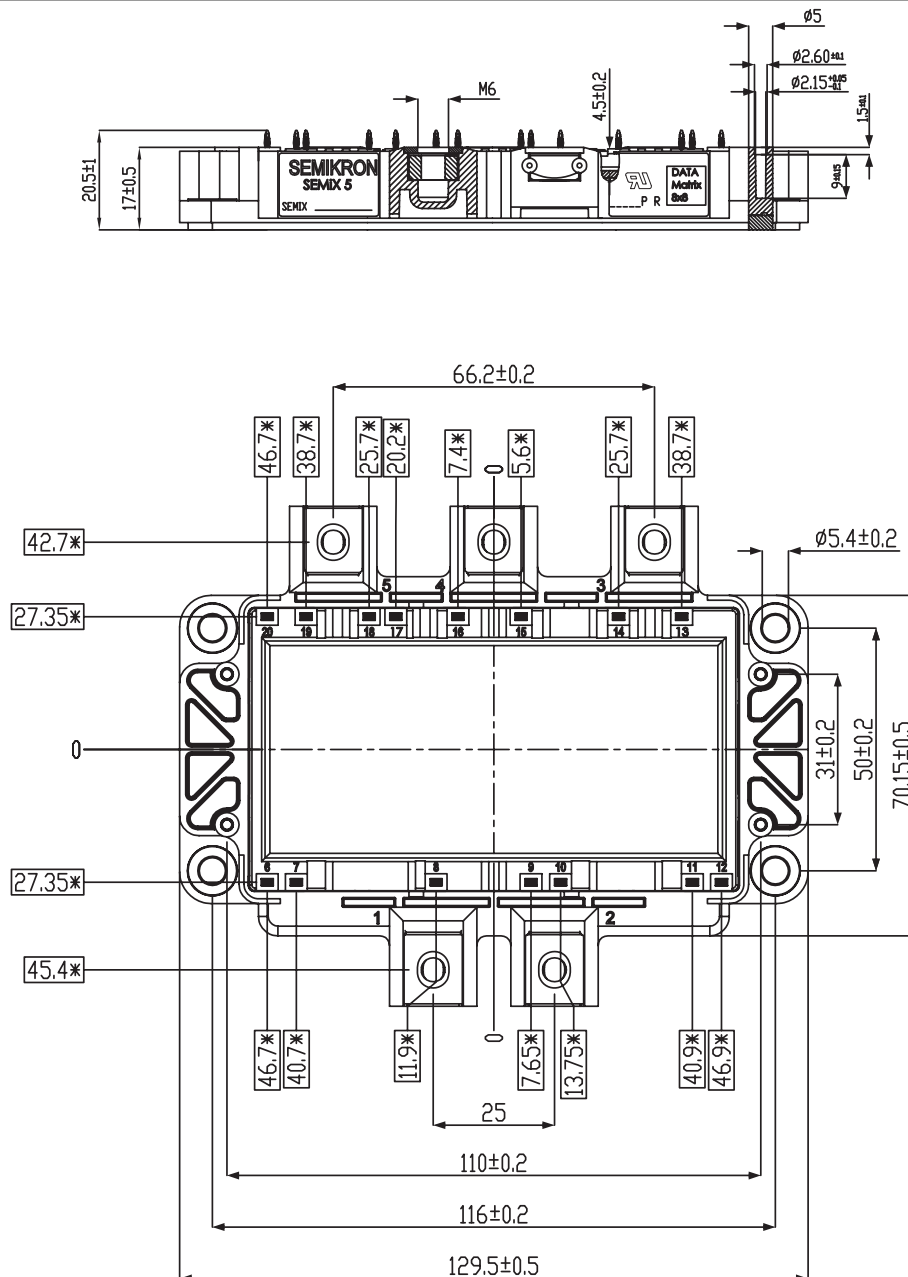


Fig. 6: Typ. gate charge characteristic

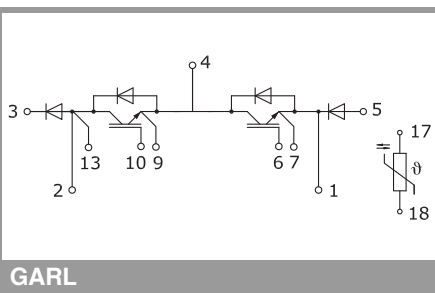




* = All dimensions with tolerance of ± 0.4

For technical details please refer
to SEMiX(R)5 Mounting Instruction

SEMiX5p



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This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, chapter IX.

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